Dobrý den,

jako zadavatel veřejné zakázky s názvem "Rastrovací Augerova mikroskopie – CEITEC MU" zasíláme tímto dodavatelům veřejné zakázky v souladu s ustanovením § 49 odst. 4 zákona č. 137/2006 Sb., o veřejných zakázkách, v platném znění, dodatečné informace č. 2 k zadávacím podmínkám.

Na základě reakce zadavatele na dodatečné informace č. 1 (znění dodatečných informací č. 1 - viz. příloha této zprávy), poskytuje zadavatel těmito dodatečnými informacemi č. 2 odpovědi na dotazy uchazeče Měřící technika Morava s.r.o., se sídlem 1. máje 102, 664 84 Zastávka, IČ: 29316715, položených prostřednictvím dodatečných informací č. 1.

Dotaz uchazeče č. 1:

In the line Fast entry chambre you wrote: „Fast entry chamber is used to introduce and to transport samples into the analytical chamber without breaking vacuum. Fast entry chamber and analytical chamber are separated by a valve and interlock."

Question: Do we understand the specification right if we assume it would be fulfilled by a system that has a manual gate valve between the fast entry chamber and the analytical chamber as a separation and an interlock for vacuum protection between the analytical chamber and the pumping system?

Odpověď zadavatele:

Yes, the interlock for vacuum protection between the analytical chamber and the pumping system is sufficient. The valve between the fast entry chamber and the analytical chamber can be manually operated.

Dotaz uchazeče č. 2:

In the line Sample holder you wrote: „The sample holder has at least four electrical contacts, the sample can also be connected to two impedance matching wires with connectors for the transmission of high frequencies up to 6 GHz at least."

Question: Do we understand the specification right if we assume it would be fulfilled by connectors which are rated for 6 GHz? We will confirm the specifications by providing the specifications sheet of the third party provider.

Odpověď zadavatele:

Yes, the specifications will be fulfilled by supplying connectors rated for 6 GHz.

Dotaz uchazeče č. 3:

In the line Beam current you wrote: „The beam current in a minimum of 50 nA at an energy of 15 keV and a resolution of 12 nm and 28 nA at 3 keV energy with resolution 18 nm. Resolution measured by 20% - 80%."

Question: Do we understand the specification right if this is a general third party vendor specification and we prove this resolution by dark apace resolution on a Au-C sample during the acceptance test?

Odpověď zadavatele:

Yes, the demonstration of the resolution on the on an Au-C sample is acceptable.

Dotaz uchazeče č. 4:

In the line Detection you wrote: „The total pulse counting detection with > 70 Mcps (Mega counts per second) integral count rate for a minimum of 7 channels and variable slit mechanism for optimisation of the resolution."

Question: Do we understand the specification right if the >70 Mcps integral count rate is a general specification of the analyzer? During the acceptance test we would show the following:

Intensity > 12000 cps per nA and channel for the 352 eV Ag peak at CRR 4 (0.5% resolution), i.e.

> 420 000 cps for typical configuration (5 nA, 7 channels)

Intensity at 5 keV primary beam energy, with sample tilt 30°* with respect to primary beam, ion-sputtered Ag sample bulk material. Working distance: 8 mm. Beam current measured using a Faraday-cup.

Signal is: peak intensity minus background.

Odpověď zadavatele:

Yes, the acceptance test described in the question is sufficient.

Dotaz uchazeče č. 5:

In section SEM, SAM in the line Image drift you wrote: „Image drift is <10 nm/10 hours. The system alows controled compensation of the drift."

And in the section SEMPA, line Image drift you wrote: „Size of image drift <10 nm/10 hours. The system allows control drift compensation. „

Question: Do we understand the specification right if we assume it would be fulfilled by having image features staying in a radius of 10 nm in 10 hrs as shown on the screen image during the acceptance?

Odpověď zadavatele:

Yes, the image drift can be demonstrated by having the image features staying in a radius of 10 nm as shown on the screen.

S pozdravem

JUDr. Pavel Vacek
právník CEITEC MU

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